

## Transparent Megahertz Circuits from Solution-processed Composite Thin Films

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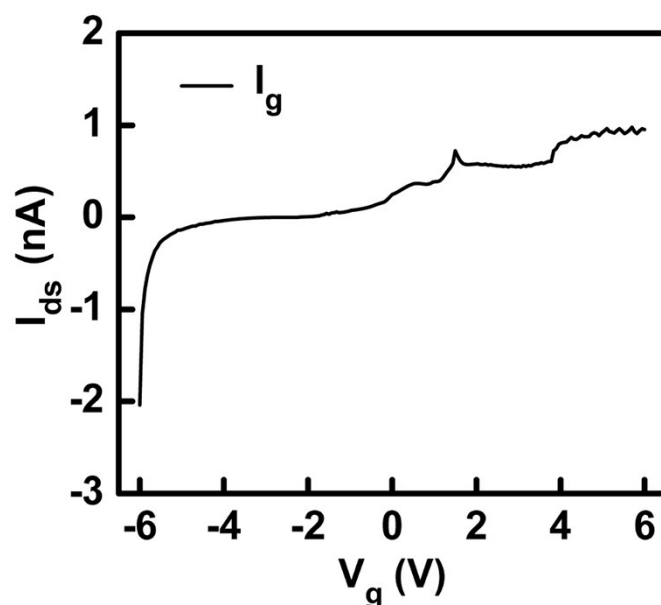
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### Supplementary Information

#### 1. Typical gate current of the solution-processed a-IGZO/SWNTs composite TFT.



**Figure S1.** Typical gate current of the solution-processed a-IGZO/SWNTs composite TFT with 30 nm HfO<sub>2</sub> dielectric layer. The current was measured at  $V_{ds}=3$  V and  $V_g$  swept from -6 V to 6 V.